

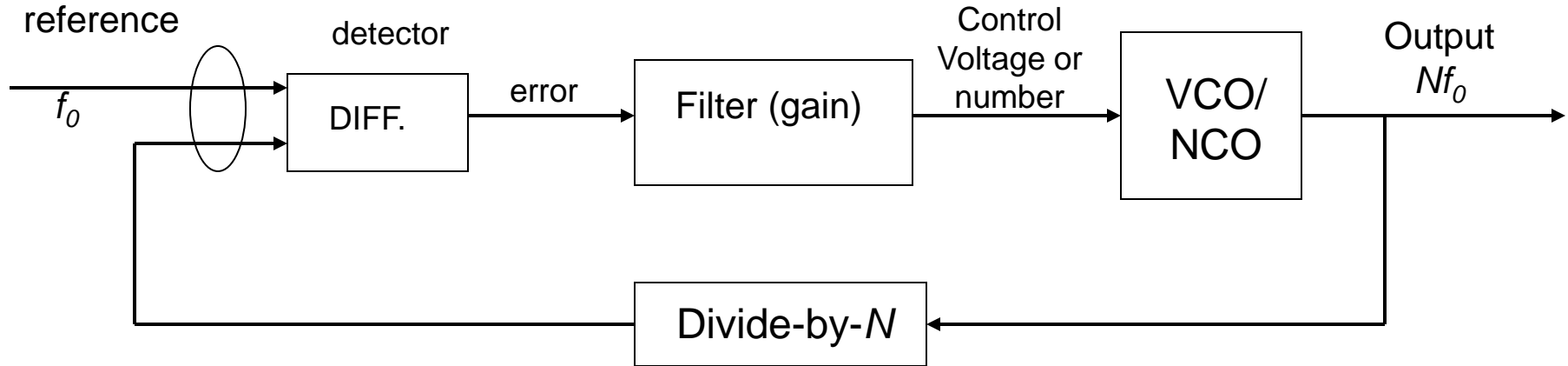
INTRODUCTION TO CLOCKS

- ▶ Clocks and Oscillators
- ▶ Timing models for clocks and “locked loops”
- ▶ Fundamental Clock Concepts and Metrics
 - ▶ Time Interval Error
 - ▶ MTIE
 - ▶ TDEV

- ▶ Distinction is more in terms of emphasis
 - ▶ Both entities relate to time/frequency
 - ▶ Both entities have the notion of periodicity (time-base)
 - ▶ Both entities provide “edges”, but –
 - ▶ Clocks usually associated with edges (square waves) (digital)
 - ▶ Oscillators usually associated with waveforms (sine waves) (analog)

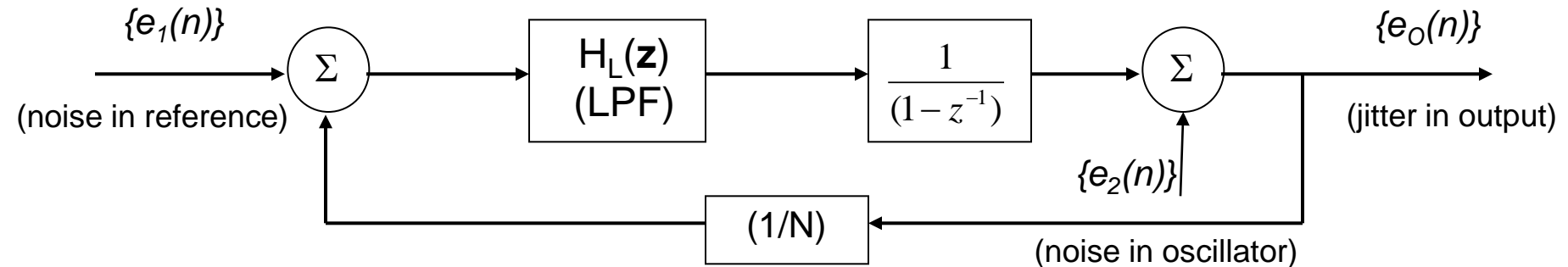
- ▶ Clock: Device/system that provides timing signals to other devices/systems
 - ▶ Emphasis is on time (time interval) accuracy
 - ▶ There is the notion of calibration (traceability to UTC)
 - ▶ A clock is a “disciplined” oscillator

- ▶ Oscillator: Component providing periodic signals
 - ▶ Emphasis is on frequency stability (temperature, aging)
 - ▶ Waveform integrity is important (“phase noise”)
 - ▶ Oscillators are components of clocks

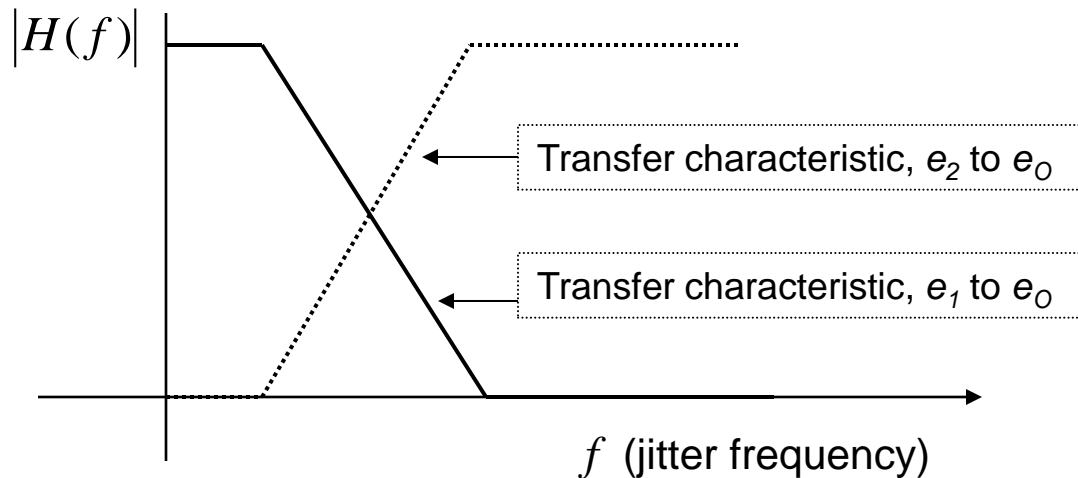


- ▶ Closed loop to discipline oscillator to align with reference
- ▶ What if reference fails ... Holdover operation
 - ▶ retain the last “good” value for control voltage/value
- ▶ What happens then?
 - ▶ frequency initially “good” (assuming instantaneous operation)
 - ▶ drift away (aging, temperature, noise, etc.)
 - ▶ “stable” value will be better than value associated with stratum
 - ▶ quality of oscillator becomes the determining factor

Analytical Model of Locked Loop



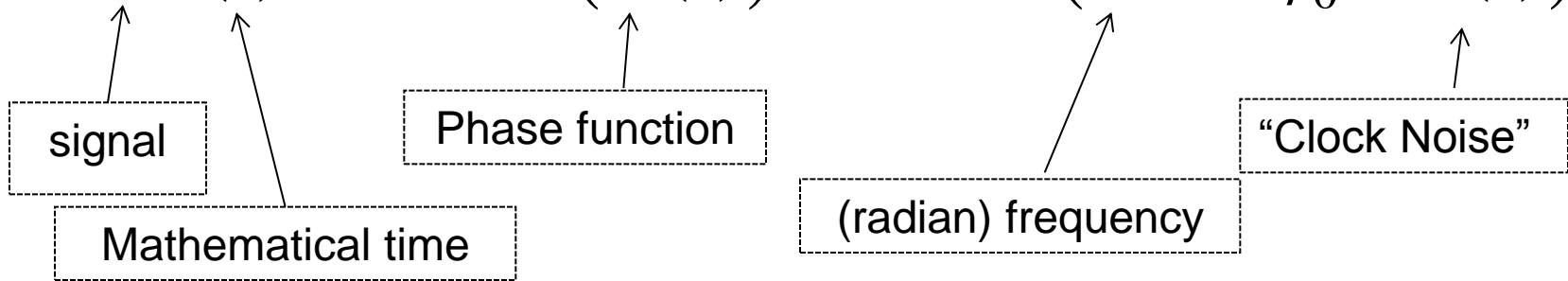
(for illustration only)



- High-freq. Noise (jitter) in output depends on the oscillator.
- Low-freq. noise (wander) depends on the reference.
- Narrow-band (LPF) implies a long time-constant.
- How large time-constant can be is governed by TDEV(τ) of oscillator and reference (flicker floor)

Common Mathematical Models

$$clock(t) = A \cdot \cos(\Phi(t)) = A \cdot \cos(\omega \cdot t + \phi_0 + \varepsilon(t))$$

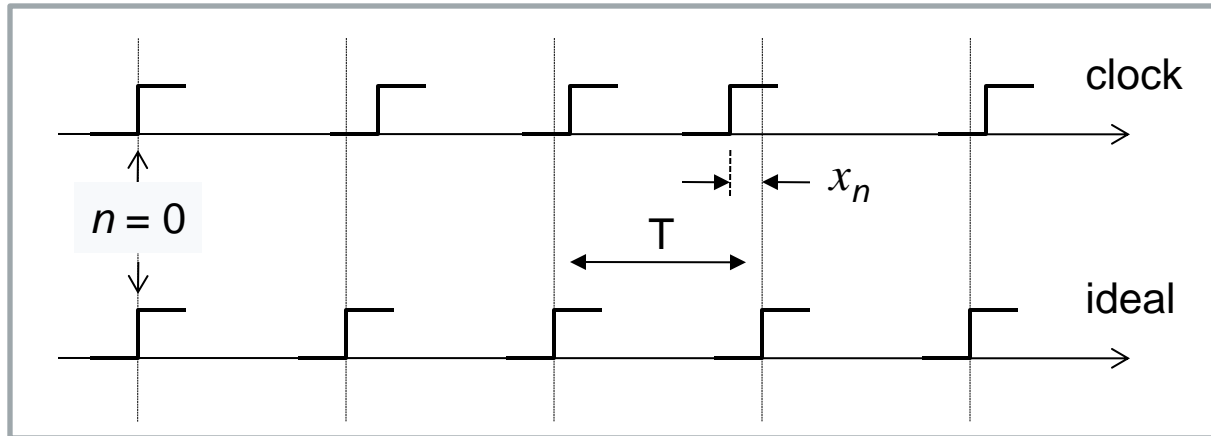


- A : Amplitude of signal. Does not figure in timing metrics.
- ϕ_0 : Initial phase. Depends on choice of time origin. Usually assumed to be 0.
- $\varepsilon(t)$: Can be further decomposed into different categories such as frequency error, frequency drift, and random noise components
- ideal periodic signal: $\Phi(t)$ is a linear function of t ($\varepsilon(t) \equiv 0$)

$$x(t) = a_0 + y \cdot t + \left(\frac{1}{2}\right) \cdot D \cdot t^2 + \phi(t)$$

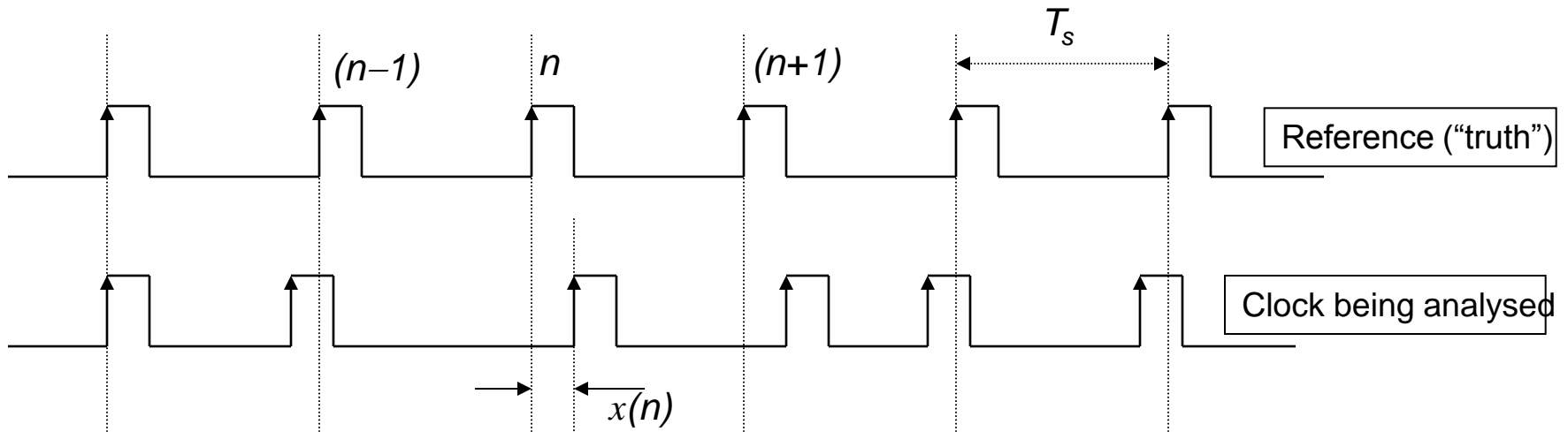
$$x(nT_s) = a_0 + y \cdot nT_s + \left(\frac{1}{2}\right) \cdot D \cdot (nT_s)^2 + \phi(nT_s)$$

Time Error Models



- ▶ Clock signals are (approximately) periodic (nominal period $\sim T$)
- ▶ Errors:
 - ▶ Edge does not line up – *phase error* (expressed in time units)
- ▶ Time Error Sequence : $\{x_n\}$ or $\{x(n)\}$
 - ▶ All clock metrics derived from time error sequence
 - ▶ Note: the time error varies “slowly” so we do not need every edge of a high-speed signal and can divide down to a convenient rate (e.g. 4 kHz or even less) (However: careful when dividing down)
 - ▶ Common assumption: $x_0 = 0$.

Time Interval Error



Basic premises:

- Both reference and clock being analyzed have same *nominal* period, T_s
- The *nominal* value for $x(n)$ is zero (or a constant)
- $T_0 = 0$ (common assumption) $\Rightarrow x(n) = n \cdot T_s - T_n$

The discrete-time signal $\{x(n)\}$ is the “Time Interval Error” (TIE) and is the basis for quantifying the performance of the clock (relative to reference)

$\{x(n)\}$ can be viewed as the samples of a (analog) signal, $x(t)$, taken every T_s seconds (implied sampling rate = $f_s = 1/T_s$) [Think DSP]

MTIE

A measure of peak-to-peak excursion expected within a given interval, τ (τ is a parameter). The observation interval is scanned with a moving window of duration τ and $MTIE(\tau)$ is the maximum excursion.

Given a set of N observations $\{x(k); k=0, 1, 2, \dots, (N-1)\}$, with underlying sampling interval τ_0 , let $\tau = n \cdot \tau_0$ (“window” = n samples; $n = 1, 2, \dots, N$).

Peak-to-peak excursion over n samples starting with sample index i is:

$$\text{peak-to-peak}(i) = \left\{ \max_{k=i}^{k=i+n-1} x(k) - \min_{k=i}^{k=i+n-1} x(k) \right\}$$

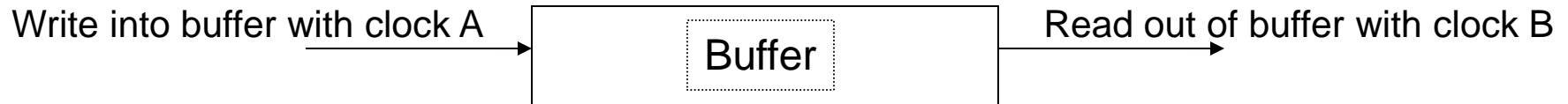
$MTIE(n)$, or $MTIE(\tau)$, is the largest value of this peak-to-peak excursion:

$$MTIE(n) = \max_{i=0}^{N-n} \left\{ \max_{k=i}^{k=i+n-1} x(k) - \min_{k=i}^{k=i+n-1} x(k) \right\}$$

Clock Metrics – MTIE and TDEV

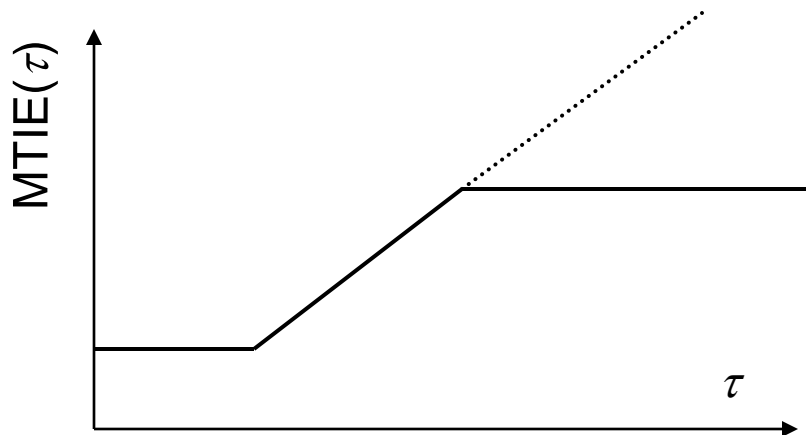
MTIE

MTIE is a useful indicator of the size of buffers and for predicting buffer overflows and underflows.



Buffer size $>$ $MTIE(\tau)$ implies that overflow/underflow unlikely in any interval $<$ τ

Buffer size = $MTIE(\tau)$ implies that overflow/underflow occurs approx. every τ seconds



Observations regarding MTIE:

- monotonically increasing with τ
- linear increase indicates freq. offset
- for small τ , $MTIE(\tau) \leftrightarrow$ jitter
- for medium τ , $MTIE(\tau) \leftrightarrow$ wander
- for large τ , indicates whether “locked”

Clock Metrics – MTIE and TDEV

TDEV

A measure of stability expected over a given observation interval, τ (τ is a parameter).

Given a set of N observations $\{x(k); k=0, 1, 2, \dots, (N-1)\}$ with underlying sampling interval τ_0 , let $\tau = n \cdot \tau_0$ (“window” = n samples; $n = 1, 2, \dots, N$).

$$\sigma_x(\tau) = TDEV(\tau) = \sqrt{\frac{1}{6n^2(N-3n+1)} \sum_{j=0}^{N-3n} \left[\sum_{i=j}^{n+j-1} (x_{i+2n} - 2x_{i+n} + x_i) \right]^2}$$

for $n=1, 2, \dots, \lfloor \frac{N}{3} \rfloor$

Conventional
Definition

Note: $x(k) \Leftrightarrow x_k$

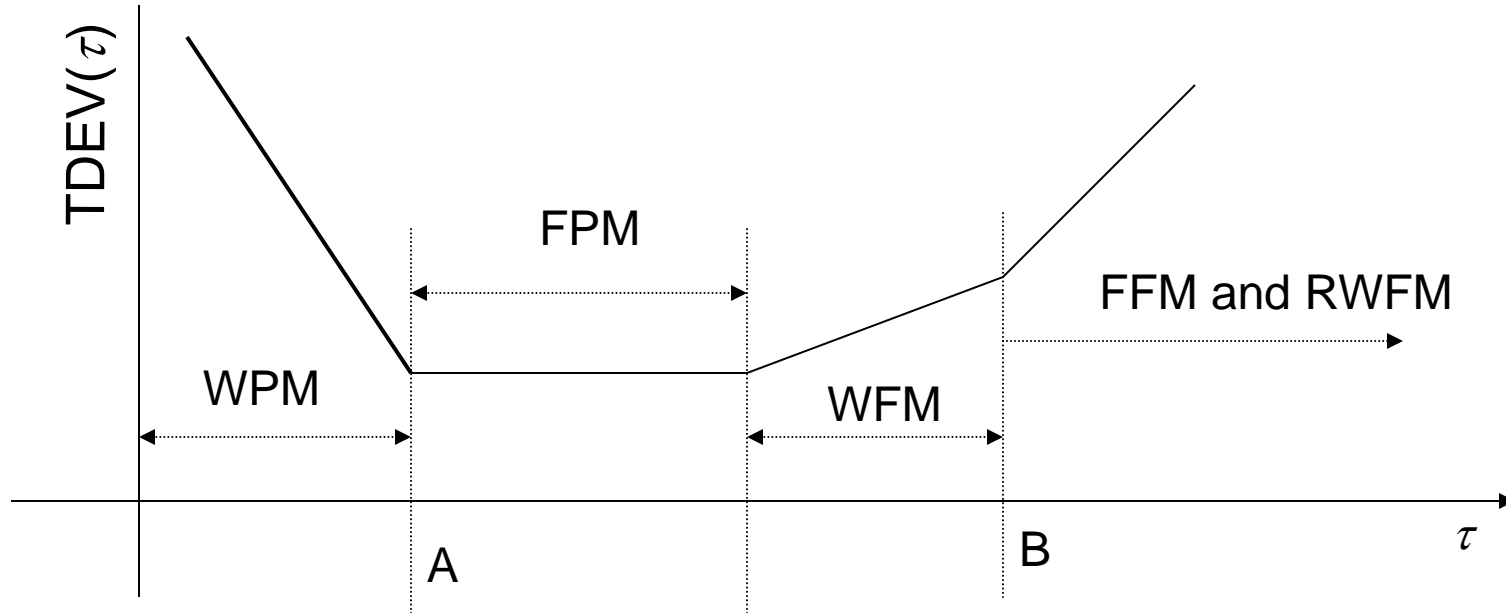
TVAR = square of TDEV

Modified Allan Variance (related to TDEV) : $\sigma_y(\tau) = \frac{\sqrt{3}}{\tau} \sigma_x(\tau)$

TDEV suppresses initial phase and frequency offset and quantifies the strength of the frequency drift and noise components {i.e. $\varepsilon(t)$ }

TDEV provides guidance on the noise process type.

Implication of TDEV(τ) versus τ



“Phase coherence” for up to A sec.

⇒ Keep PLL time constants less than A sec.

Phase Flicker Floor

“Frequency coherence” for up to B sec.

⇒ Keep FLL time constants less than B sec.

Frequency Flicker Floor